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LIST OF REFERENCES CITED BY APPLICANT				Hideo ANDO, et al.					
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b.	AX	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No. AD00103788 (English Translation).							
Re	AY	Explanation of Circums (English Translation).	tances Concer	rning Accelerated Examination for Japan	ese Pateni	t Applicatio	n No. AD00103787		
- 1	AZ				Additional References sheet(s) attached				
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